TOSHIBA Photocoupler GaAs Ired & Photo-Transistor

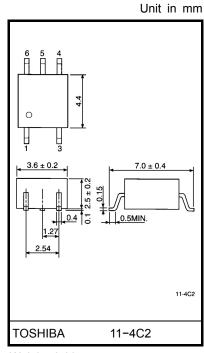
TLP131

Office Machine Programmable Controllers AC / DC–Input Module Telecommunication

The TOSHIBA mini flat coupler TLP131 is a small outline coupler, suitable for surface mount assembly. TLP131 consists of a photo transistor, optically coupled to a gallium arsenide infrared emitting diode.

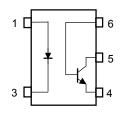
- Collector-emitter voltage: 80V (min.)
- Current transfer ratio: 50% (min.) Rank GB: 100% (min.)
 - Isolation voltage: 3750Vrms (min.)
- UL recognized: UL1577, file No. E67349

TLP131 base terminal is for the improvement of speed, reduction of dark current, and enable operation.



Weight: 0.09 g

Pin Configurations (top view)





3 : Cathode 4 : Emitter

5 : Collector

6 : Base

Current Transfer Ratio

Туре	Classification	Ratio (I _C	Transfer o (%) / I _F) = 5V, Ta = 25°C	Marking Of Classification		
		Min.	Max.			
	(None)	50	600	BLANK, Y, Y [∎] , G, G [∎] , B, B [∎] , GB		
TLP131	Rank Y	50	150	Y, Y*		
ILF 131	Rank GR	100	300	G, G ⁼		
	Rank GB	100	600	G, G [∎] , B, B [∎] , GB		

Note: Application type name for certiffication test,please use standard product type name,i.e. TLP131(GB): TLP131

Absolute Maximum Ratings (Ta = 25°C)

	Characteristic	Symbol	Rating	Unit
	Forward current	IF	50	mA
	Forward current derating (Ta≥53°C)	ΔI _F / °C	-0.7	mA / °C
LED	Peak forward current (100µs pulse,100pps)	I _{FP}	1	А
	Reverse voltage	V _R	5	V
	Junction temperature	Tj	125	°C
	Collector-emitter voltage	V _{CEO}	80	V
	Collector-base voltage	V _{CBO}	80	V
	Emitter-collector voltage	V _{ECO}	7	V
Ŀ	Emitter-base voltage	V _{EBO}	7	V
Detector	Collector current	Ι _C	50	mA
ă	Peak collector current (10ms pulse,100pps)	I _{CP}	100	mA
	Power dissipation	PC	150	mW
	Power dissipation derationg (Ta ≥ 25°C)	ΔP _C / °C	-1.5	mW / °C
	Junction temperature	Тj	125	°C
Stor	age temperature range	T _{stg}	-55~125	°C
Ope	erating temperature range	T _{opr}	-55~100	°C
Lea	d soldering temperature (10s)	T _{sol}	260	С°
Tota	al package power dissipation	PT	200	mW
Tota	al package power dissipation derating (Ta $\ge 25^{\circ}$ C)	ΔP _T / °C	-2.0	mW / °C
Isol	ation voltage (AC, 1min., RH≤ 60%) (Note 1)	BVS	3750	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Device considered a two terminal device: Pins 1 and 3 shorted together, and pins 4, 5 and 6 shorted together.

Recommended Operating Conditions

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V _{CC}	_	5	48	V
Forward current	١ _F	_	16	25	mA
Collector current	ΙC	_	1	10	mA
Operating temperature	T _{opr}	-25		85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Individual Electrical Characteristics (Ta = 25°C)

	Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
	Forward voltage	VF	I _F = 10 mA	1.0	1.15	1.3	V
LED	Reverse current	I _R	V _R = 5 V	_	_	10	μA
	Capacitance	CT	V = 0, f = 1 MHz	_	30	_	pF
	Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C = 0.5mA	80	_	_	V
	Emitter–collector breakdown voltage	V _{(BR)ECO}	I _E = 0.1mA	7	_	_	V
	Collector-base breakdown voltage	V _{(BR)CBO}	I _C = 0.1mA	80	_	_	V
	Emitter-base breakdown voltage	V _{(BR)EBO}	I _E = 0.1mA	7	_	—	V
ector	collector dark current	ICEO	V _{CE} = 48V	—	10	100	nA
Dete			V _{CE} = 48V,Ta = 85°C	—	2	50	μA
	Collector dark current	ICER	V _{CE} = 48V,Ta = 85°C R _{BE} = 1MΩ	_	0.5	10	μA
	Collector dark current	I _{CBO}	V _{CB} = 10V	_	0.1	_	nA
	DC forward current gain	h _{FE}	V _{CE} = 5V,I _C = 0.5mA	_	400	_	—
	Capacitance (collector to emitter)	C _{CE}	V = 0, f = 1MHz	_	10	_	pF

Coupled Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Current transfer ratio		I _F = 5 mA, V _{CE} = 5 V Rank GB	50	_	600	%
	IC / IF		100	_	600	
Saturated CTR	I _C / I _{F (sat)}	I _F = 1 mA, V _{CE} = 0.4 V Rank GB	_	60	_	- %
Saturated CTR			30	_	_	
Base photo-current	I _{PB}	I _F = 5mA,V _{CB} = 5V	_	10	_	μA
	V _{CE (sat)}	I _C = 2.4 mA, I _F = 8 mA	_	_	0.4	v
Collector–emitter saturation voltage		I _C = 0.2 mA, I _F = 1 mA Rank GB	_	0.2	_	
			_	_	0.4	
Off-state collector current	I _{C (off)}	I _F = 0.7mA, V _{CE} = 48 V	_	1	10	μA

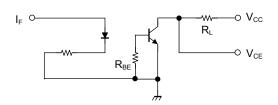
Isolation Characteristics (Ta = 25°C)

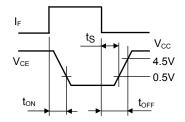
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Capacitance (input to output)	CS	V _S = 0, f = 1 MHz	_	0.8	_	pF
Isolation resistance	R _S	V _S = 500 V	5×10 ¹⁰	10 ¹⁴	_	Ω
	BVS	AC, 1 minute	3750	_	_	Vrms
Isolation voltage		AC, 1 second, in oil	_	10000	_	
		DC, 1 minute, in oil	_	10000	_	Vdc

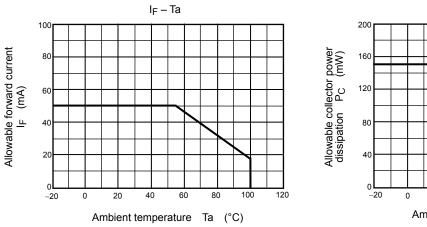
Switching Characteristics (Ta = 25°C)

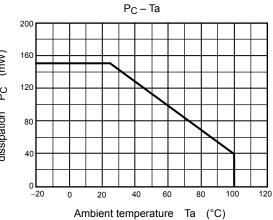
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Rise time	tr	V_{CC} = 10 V, I _C = 2 mA R _L = 100Ω	_	2	_	μs
Fall time	t _f		_	3	_	
Turn-on time	t _{on}		_	3	_	
Turn–off time	t _{off}		_	3	_	
Turn–on time	t _{ON}	R _L = 1.9 kΩ%) (Fig.1)	_	2	_	
Storage time	ts	R _{BE} = OPEN	_	25	_	μs
Turn-off time	tOFF	V _{CC} = 5 V, I _F = 16 mA	_	40	_	
Turn–on time	t _{ON}	R _L = 1.9 kΩ%) (Fig.1)		2	_	
Storage time	t _s	R _{BE} = 220 kΩ	_	20	_	μs
Turn–off time	t _{OFF}	V _{CC} = 5 V, I _F = 16 mA		30	_	

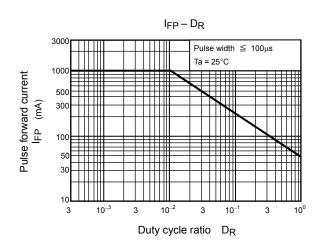
Fig. 1 Switching time test circuit

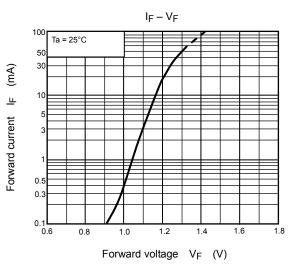


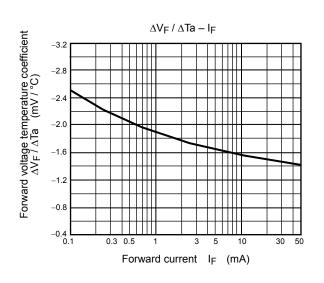


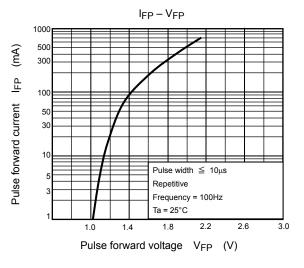


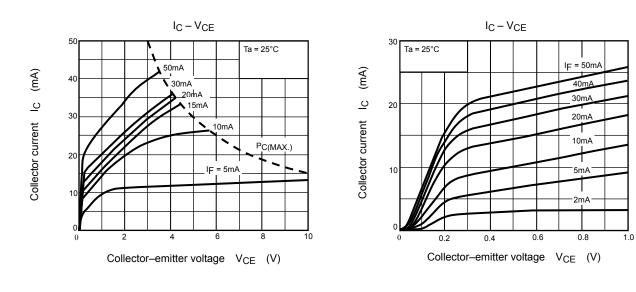


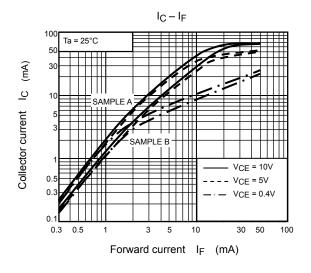


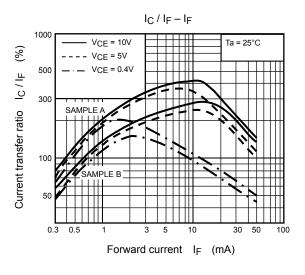


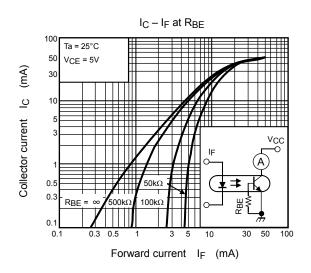


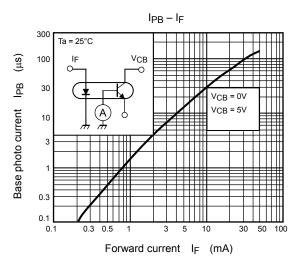


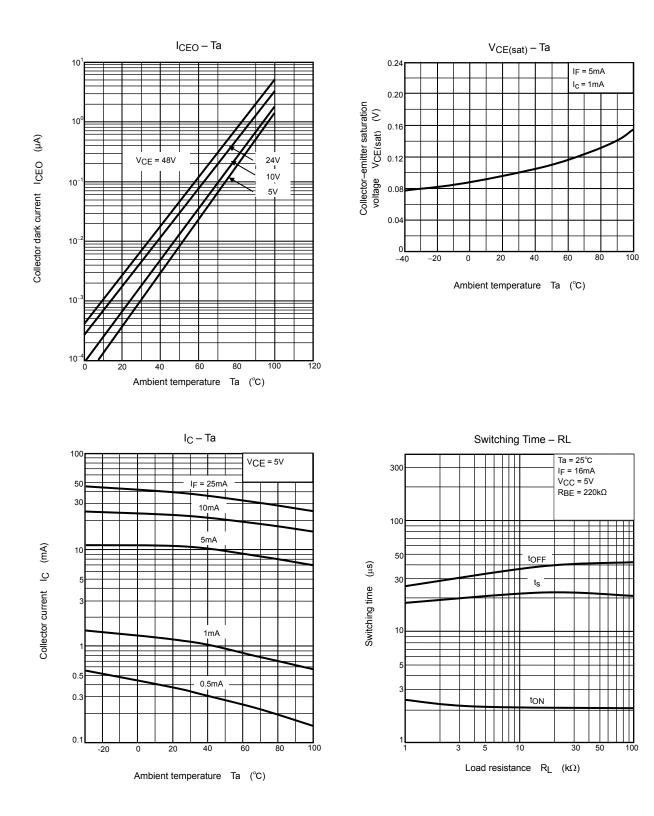




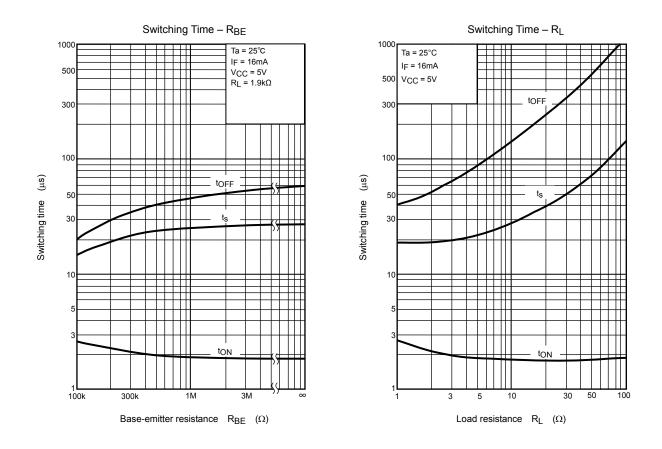








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